

Form PTO 1419  
(Modified)DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

250847US2X

SERIAL NO.

10/810,713

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Sotoshi YAMADA, et al.

FILING DATE

March 29, 2004

GROUP

2862

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
<i>Jat</i>	AO	2000-80535	03/21/2000	JAPAN (with English Abstract)		X
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

<i>Jat</i>	AW	Kazunori NAKAMURA, et al., "ECT Multi-Sensor for Inspection of Printed Circuit Boards", The 15 <sup>th</sup> Symposium on Electromagnetic and Dynamics, May 28, 2003, pages 339-342 (with English Abstract)				
<i>Jat</i>	AX	Yasuhiro KATAOKA, et al., "Detection of Eddy Current Change by Slit using GMR Line Sensor", The Papers of Technical Meeting on Magnetism, IEEE Japan (MAG), MAG-02, no. 131-136, October 23, 2002, pages 11-16 (with English Abstract)				
	AY					
	AZ					

☐ Additional References sheet(s) attached

Examiner

*Jaymabaker*

Date Considered

3/28/06

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.